

Application/Control N	lo. Applicant(s)/Patent Reexamination	t under
09/920,341	CHOI ET AL.	
Examiner	Art Unit	
Sang Nguyen	2877	

SEARCHED				
Class	Subclass	Date	Examiner	
356	601-625	4/11/2005	sz	
1	128	1		
	392-395			
-	398-401			
250	548			
	557			
	491.1	-		
73	856.8			
430	5			
	302	l l	Ų.	
4	309	4/11/2005	SN	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
same	above	4/11/2005	SN	
	<u> </u>			
		<u> </u>	<u> </u>	

(INCLUDING	SEARCH STRATEG	Y)
	DATE	EXMR
EAST	4/11/2005	SN
· · · · · · · · · · · · · · · · · · ·		-